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Q6s: USPAT:US PQPUB; EPO: JPO; DERWENT: IBM; TDD

Default operator: OR

```

(((gate) near2 (insulat$5 dielectric oxide)
) same ((insulat$5 dielectric oxide)
) near9 (different adj2 (((barrier near (height tunnel)) tunnel$4 - (energy diagram conduct$4 gap width) near band) bandgap
bandwidth (work adj function)
)
))) and ((float$4 adj (gate electrode plate trap$4) - FG) charge adj storage)
) not (((gate) near2 (insulat$5 dielectric oxide)
) same ((insulat$5 dielectric oxide)
) near9 (different adj2 (((barrier near (height tunnel)) tunnel$4 - (energy diagram conduct$4 gap width) near band) bandgap
bandwidth (work adj function)
)
))) same ((float$4 adj (gate electrode plate trap$4) - FG) charge adj storage)
)

```

oct 2004

	U	I	Inventor	Document#	Issue #	Title	Current	Current CN	Revelation	S	C	P	Image Doc.	P
1	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	Lee, Chang-H	US 2003021	20031	Electrically erasable charge trap nonvolatile	365/185			<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 200302
2	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	Choi, Woong	US 2003003	20030	Non-volatile semiconductor memory and met	365/185;257/E21.68			<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 200300
3	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	Shimizu, Shu	US 2003000	20030	Nonvolatile semiconductor memory device	365/185			<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 200300
4	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	Kang, Man-S	US 2002017	20021	Semiconductor memory device having a float	257/315			<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 200201
5	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	Lee, Woon-ky	US 2002013	20020	Method of fabricating a flash memory device	438/201;257/E21.68			<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 200201
6	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	Forbes, Leon	US 2002011	20020	Pchannel dynamic flash memory cells with u	257/315;257/E29.12			<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 200201
7	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	Forbes, Leon	US 2002009	20020	Pchannel dynamic flash memory cells with u	438/257;257/E29.12			<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 200200
8	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	Forbes, Leon	US 2002009	20020	P-channel dynamic flash memory cells with u	257/315;257/E29.12			<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 200200
9	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	Forbes, Leon	US 2001005	20011	Dynamic flash memory cells with ultra thin t	365/185			<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 200100
10	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	Shimizu, Shu	US 6728133	20040	Nonvolatile semiconductor memory device	365/185;365/185.08			<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 672813

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